## Notice of References Cited Application/Control No. 10/517,377 Examiner IAN JEN Applicant(s)/Patent Under Reexamination FURUTA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,255,753 A	10-1993	Nishikawa et al.	180/8.6
*	В	US-5,421,426 A	06-1995	De Beaucourt et al.	180/8.1
*	С	US-6,377,014 B1	04-2002	Gomi et al.	318/568.12
*	D	US-2002/0088083 A1	07-2002	Takizawa, Shigeo	16/45
*	Е	US-2002/0193045 A1	12-2002	Lee et al.	446/330
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	7	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C					
	V					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.